

Search Notes

Application/Control No.

10/727,171

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

MIZUNO ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	3,14,15,24	4/11/2006	JDS
385	39,40,49	4/11/2006	JDS
398	43,48,53	4/11/2006	JDS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
USPGPUB interference search – see attached EAST search hist		4/11/2006	JDS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	4/11/2006	JDS
IEEE INSPEC: MZI, AWG, phase, quadratic, MUX, DMUX	4/11/2006	JDS
USPGPUB interference search – see attached EAST search history	4/11/2006	JDS